

Notic of References Cited

Application/Control No.

10/005,094

Examiner

Stephen W. Smoot

Application/Control No.

Application/Control No.

Application/Control No.

Reexamination
CHOI ET AL.

Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-5,812,230	09-1998	Sakaigawa et al.	349/166
	В	US-5,566,009	10-1996	Yamazaki et al.	349/86
	С	US-5,790,217	08-1998	Lee et al.	349/86
	D	US-5,877,834	03-1999	Sako et al.	349/171
	Е	US-5,942,155	08-1999	Coles et al.	252/299.64
	ŀ	US-5,949,508	09-1999	Kumar et al.	349/122
,	G	US-6,038,009	03-2000	Miyazaki et al.	349/188
	Н	US-			
	1	US-			
	J	US-			
	K	US-			
	٦	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 4-281425 A	10-1992	Japan	KOBAYASHI, HIDEKAZU	G02F 01/1333
	0					
	Р				,	
	Q					
	R					
	s					
	Т					

NON-PATENT DOCUMENTS

	NON-FAILNI DOCUMENTO				
*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
	U	Stanley Wolf and Richard N. Tauber, "Silicon Processing for the VLSI Era - Volume 1: Process Technology," Second Edition, Lattice Press, Sunset Beach, California (2000), pp. 588-590.			
	٧	H. Furue et al., "Mesogenic Polymer Stabilized Ferroelectric Liquid Crystal Display Exhibiting Monostability with High Contrast Ratio and Grayscale Capability," Japanese Journal of Applied Physics, vol. 36, pt. 2, no. 11B, November 1997, pp. L1517-L1519.			
	w				
	х				

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.